Attorney's Docket No. Application No. Substitute Form PTO-1449 U.S. Department of Commerce 07977-024003 New Divisional (Modified) Patent and Trademark Office Application Information Disclosure Statement Applicant by Applicant Isamu Kobori et al. (Use several sheets if necessary) Filing Date Group Art Unit (37 CFR §1.98(b)) July 22, 2003 Unknown **U.S. Patent Documents** Examiner Publication Desig. Document Filing Date Initial ID Number. Date Patentee Class Subclass If Appropriate SKI ΑA 5,413,958 05/1995 Imahashi et al. AB 5,529,630 06/1996 Imahashi et al. AC 5,595,923 01/1997 Zhang et al. 5,767,930 AD 06/1998 Kobayashi et al. AE 5,854,494 05/1995 Yamazaki et al. AF 5,966,594 10/1999 Adachi et al. ÁG 5,854,096 12/1998 Ohtani et al. AH 5,712,191 01/1998 Nakajima et al. 5,731,613 .AĮ 03/1998 Yamazaki et al. ΑJ 5,937,282 08/1999 Nakajima et al. ÁK 5,959,313 09/1999 Yamazaki et al. 6,051,453 04/2000 AL Takemura AM 6,071,764 06/2000 Zhang et al.

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